

Initial Product/Process Change Notification Document #:IPCN24757X

Issue Date:30 Jun 2022

Title of Change:	Qualification of onsem	Qualification of onsemi Roznov as an additional wafer source for QFET Technology	
Proposed First Ship date:	01 Mar 2023 or earlier	01 Mar 2023 or earlier if approved by customer	
Contact Information:	Contact your local onse	Contact your local onsemi Sales Office or Yuna.Im@onsemi.com	
PCN Samples Contact:	Sample requests are to Initial PCN or Final PCN Samples delivery timin	Contact your local onsemi Sales Office. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.	
Type of Notification:	advance notification al change details and dev The completed qualific Product/Process Chang Product/Process Chang	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact < PCN.Support@onsemi.com>	
Marking of Parts/ Traceability of Change:	Changed material can be identified by lot code		
Change Category:	Wafer Fab Change	Wafer Fab Change	
Change Sub-Category(s):	Manufacturing Site Ad	Manufacturing Site Addition	
Sites Affected:			
onsemi Sites		External Foundry/Subcon Sites	
onsemi Bucheon, Korea		None	
onsemi Roznov, Czech Republic			

Description and Purpose:

This is an Initial Change Notification to inform customers of the qualification of onsemi Roznov, Czech Republic as an additional wafer fab location for QFET Technology. Upon the expiration of this notification, all products listed here will be dual sourced from onsemi Bucheon, Korea and onsemi Roznov Czech Republic.

	From	То
Fab Site	onsemi,Bucheon, Korea	onsemi, Bucheon, Korea onsemi Roznov Czech Republic
Wafer size	6inch	6inch

There is no product marking change as a result of this change.

TEM001790 Rev. F Page 1 of 4



Initial Product/Process Change Notification Document #:IPCN24757X

Issue Date:30 Jun 2022

Qualification Plan:

QV DEVICE NAME: FQA28N50

RMS: K84460 PACKAGE: TO-3P

Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj=150°C, 80% Rated BV	1008 hrs
HTGB	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs
HTSL	JESD22-A103	Ta=Max rated storage temp(150°C)	1008 hrs
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off =5 min	6,000 cyc
TC	JESD22-A104	Ta= -55°C to +150°C	1,000 cyc
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias 42V	96 hrs
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

QV DEVICE NAME: FQA70N15

PACKAGE: TO-3P

Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj=150°C, 80% Rated BV	1008 hrs
HTGB	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs
HTSL	JESD22-A103	Ta=Max rated storage temp	1008 hrs
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off =5 min	6,000 cyc
TC	JESD22-A104	Ta= -55°C to +150°C	1,000 cyc
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias 42V	96 hrs
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs

TEM001790 Rev. F Page 2 of 4



Initial Product/Process Change Notification Document #:IPCN24757X

Issue Date:30 Jun 2022

QV DEVICE NAME: FQD2N100TM

PACKAGE: DPAK

Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj=150°C, 80% Rated BV	1008 hrs
HTGB	JESD22-A108	Ta=150°C, 100% max rated Vgss	1008 hrs
HTSL	JESD22-A103	Ta=Max rated storage temp	1008 hrs
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	15,000 cyc
TC	JESD22-A104	Ta= -55°C to +150°C	1,000 cyc
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias 42V	96 hrs
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs
PC	J-STD-020 JESD-A113	MSL1 @ 260 °C	

QV DEVICE NAME: FSL137MRIN

RMS: K84366 **PACKAGE: PDIP-8**

Test	Specification	Condition	Interval
HTOL	JESD22-A108	Ta=110℃, 100% max rated Vcc	1008 hrs
HTSL	JESD22-A103	Ta=150°C	1008 hrs
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96hrs
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96hrs

Estimated date for qualification completion: 1 December 2022

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Part Number	Qualification Vehicle
FSL137MRIN	FQD2N100TM, FSL137MRIN
FQT4N20LTF	FQA28N50, FQA70N15, FQD2N100TM
FQD19N10LTM	FQA28N50, FQA70N15, FQD2N100TM

TEM001790 Rev. F Page 3 of 4



Initial Product/Process Change Notification Document #:IPCN24757X Issue Date:30 Jun 2022

FQD7P20TM	FQA28N50, FQA70N15, FQD2N100TM
FQD3P50TM	FQA28N50, FQA70N15, FQD2N100TM
FQB27P06TM	FQA28N50, FQA70N15, FQD2N100TM
FQB4N80TM	FQA28N50, FQA70N15, FQD2N100TM
FQB5N90TM	FQA28N50, FQA70N15, FQD2N100TM
FQA13N80-F109	FQA28N50, FQA70N15, FQD2N100TM
FQA24N60	FQA28N50, FQA70N15, FQD2N100TM
FQB47P06TM-AM002	FQA28N50, FQA70N15, FQD2N100TM

TEM001790 Rev. F Page 4 of 4